

SSLS
EFRC

SOLID-STATE LIGHTING SCIENCE
ENERGY FRONTIER RESEARCH CENTER

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Application of a microscopic model to efficiency droop of InGaN LEDs

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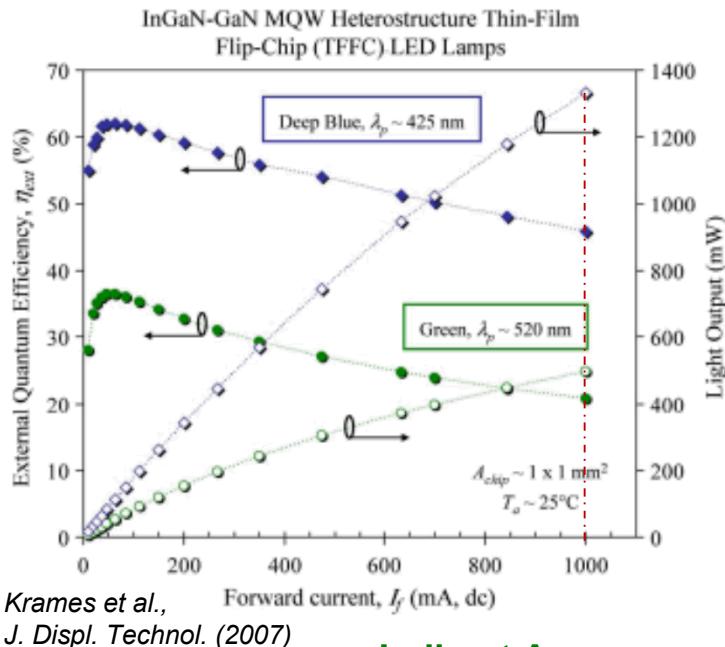
Sandia National Laboratories

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Motivation: High Efficiency InGaN LEDs for Solid State Lighting



Primary Efficiency Limitations

- High operating currents (“efficiency droop”)
- High operating temperatures
- Longer wavelengths (e.g., green and longer)

Recombination model:

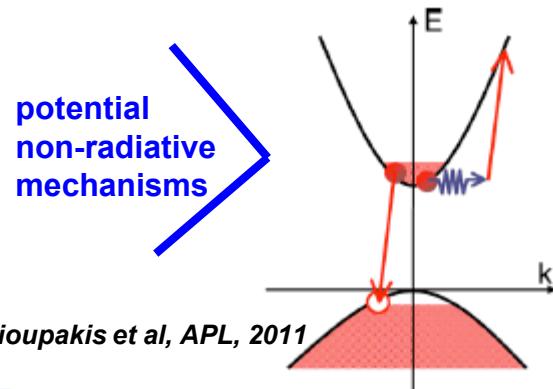
$$\mathcal{E}_{IQE} = \frac{Bn^2}{An + Bn^2 + Cn^3 + Dn^m + \dots}$$

Shockley-Read-Hall
(nonrad at defects)

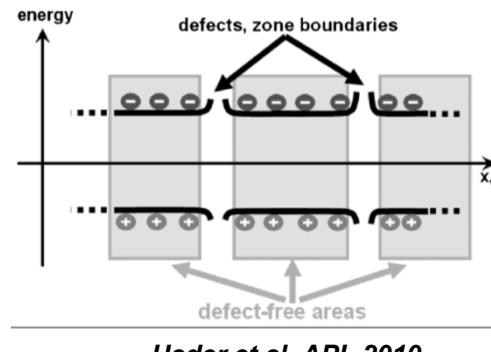
Radiative

Auger and higher
order processes

Indirect Auger recombination



Carrier delocalization/ defect recombination



Carrier capture / leakage

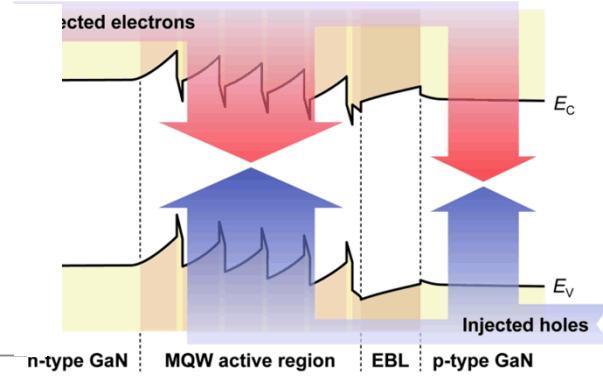


Figure: E. F. Schubert

I. Application of a Microscopic Model to Study Efficiency Limitations in InGaN LEDs

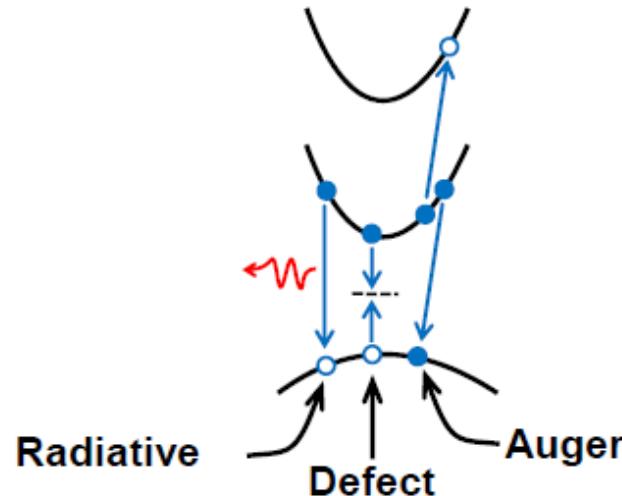
LED rate-equation model (“ABC”)

$$\frac{dN}{dt} = \frac{J}{ed} - AN - BN^2 - CN^3$$

↑ Defects ↑ Spontaneous emission ↑ Auger?

Internal quantum efficiency = $\frac{BN^2}{AN + BN^2 + CN^3}$

Radiative and Non-radiative Processes



Model Shortcomings:

- a) True density dependence not simple N^m
- b) Carrier capture/leakage ignored
- c) Plasma heating and other non-equilibrium effects ignored

Approach:

- Advance rate equation model:
 - microscopic radiative component
 - non-equilibrium effects
- Explore non-linear contributions of defect-related recombination

Model Approach

“ABC” Quasi equilibrium model
(phenomenological rate equations)

k-resolved, relaxation rate
approx.

k-resolved, quantum
kinetic theory

Key Advances from “ABC” model

→ Replace total “N” with k-resolved distributions
→ *bandstructure implemented directly into model*

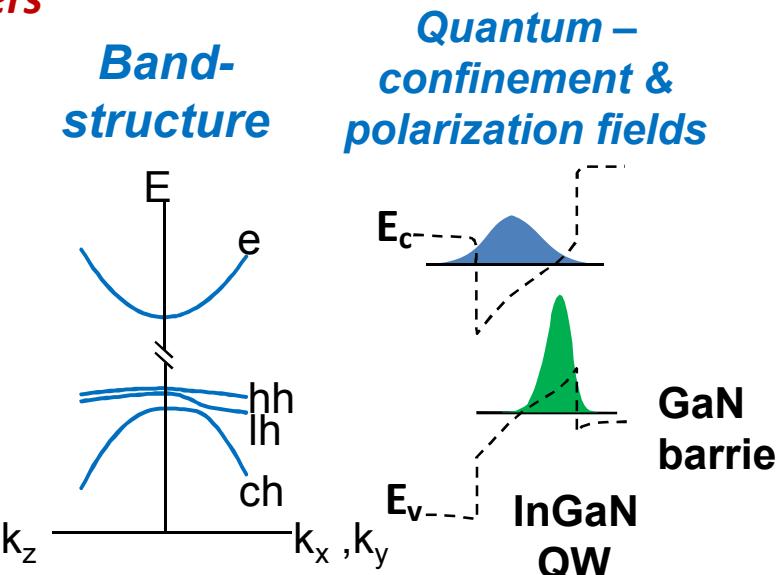
$$N = \sum_k n_{e(h),k}$$

→ Track carrier distributions in both QWs and barriers
→ treatment of carrier injection and leakage

→ Carrier-carrier and carrier-phonon interactions
→ Relaxation rate approximation

$$\frac{\partial n_{\sigma,\alpha_\sigma,k_\perp}}{\partial t} \Big|_{col} = -\gamma_{e-e} [n_{\sigma,\alpha_\sigma,k_\perp} - f_{\sigma,\alpha_\sigma,k_\perp}(\mu_\sigma^p, T_p)] - \gamma_{e-p} [n_{\sigma,\alpha_\sigma,k_\perp} - f_{\sigma,\alpha_\sigma,k_\perp}(\mu_\sigma^l, T_l)]$$

→ Calculate radiative contribution directly
→ avoids constant B parameter



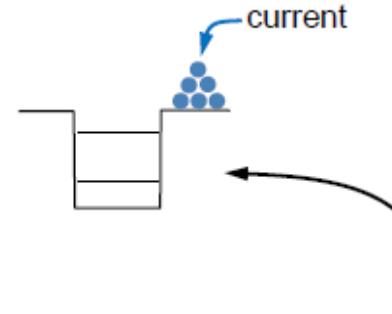
$$\frac{dN}{dt} = \frac{J}{ed} - AN - BN^2 - CN^3$$

↑ Defects ↑ Spontaneous emission ↑ Auger?

Summary of model and equations

Carrier injection

New Model



Similar for holes

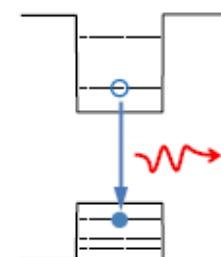
Barrier:

$$\frac{dn_{\sigma,k}^b}{dt} = \frac{J(t)}{eN_\alpha^p} f(\varepsilon_{\sigma k}^b, \mu_\alpha^p, T_p) (1 - n_{\sigma,k}^b) - A_b n_{\sigma,k}^b + \frac{\partial n_{\sigma,k}^b(t)}{\partial t} \Big|_{col}$$

QW:

$$\frac{dn_{\sigma,\alpha_\sigma,k_\perp}}{dt} = -n_{\sigma,\alpha_\sigma,k_\perp} \sum_{\alpha_{\sigma'}} \frac{p_{\alpha\beta k}^2 \Omega_k^3}{\pi \epsilon \hbar c^3} n_{\sigma',\alpha_{\sigma'},k_\perp} - A n_{\sigma,\alpha_\sigma,k_\perp} + \frac{\partial n_{\sigma,\alpha_\sigma,k_\perp}}{\partial t} \Big|_{col}$$

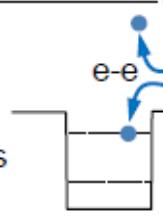
Spontaneous emission (>ns)



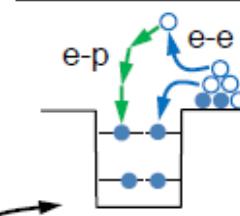
$$\tau = CN^2$$

IEEE JQE 38 402, 2002 (for QW)
IEEE JQE 41 495, 2005 (for QD)

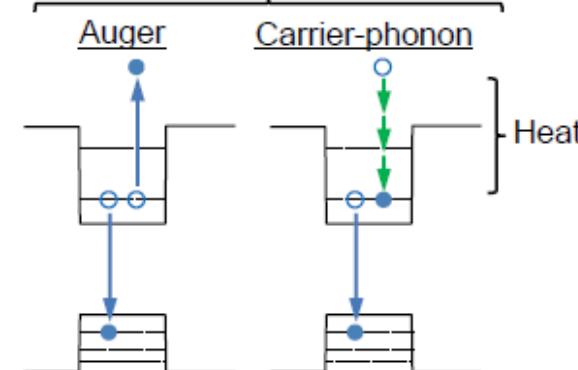
Carrier-carrier (100fs)



Carrier-phonon (1ps)



Auger



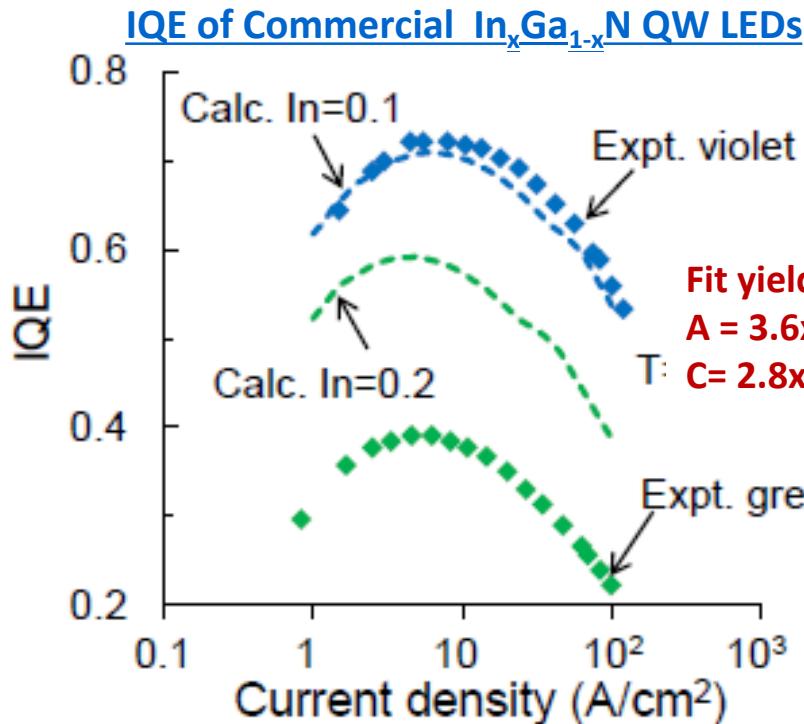
Carrier-phonon



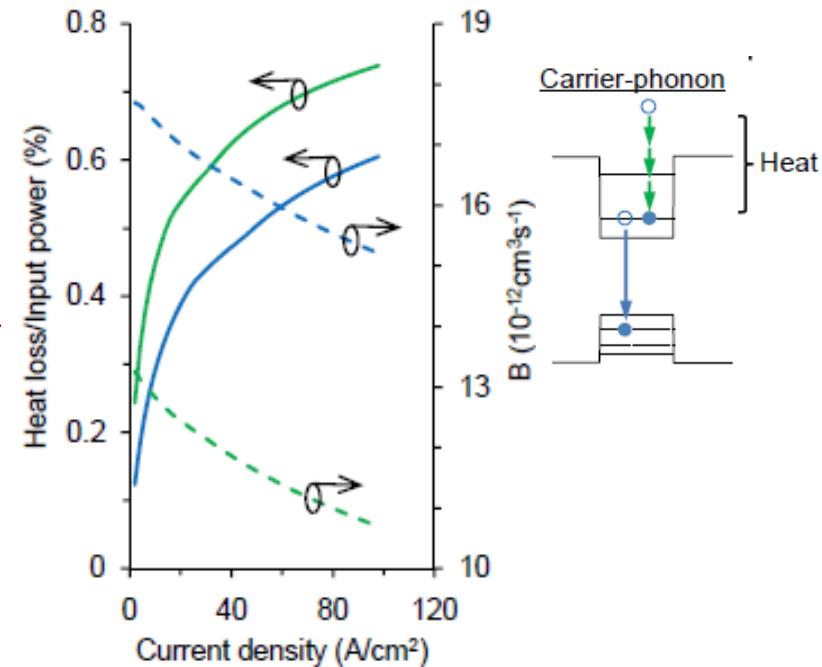
Contributions to LED Efficiency Dependence on Wavelength

Outstanding issue: why are longer wavelength (green) InGaN LEDs less efficient ?

→ hypotheses: increased strain/polarization fields, increased non-radiative defects



Contributions to lower green efficiency



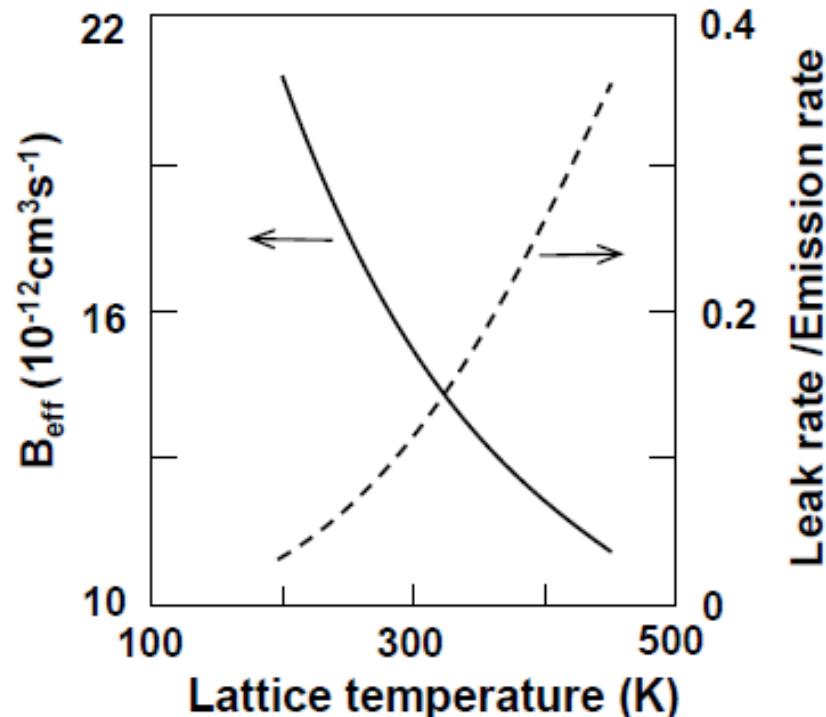
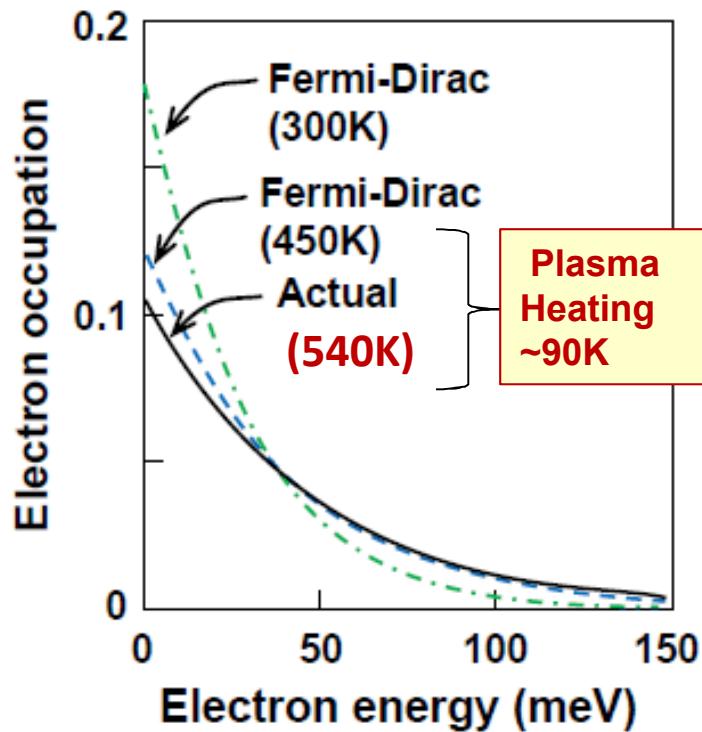
Model insights: ~1/3 of difference between violet and green LED efficiency is due to **intrinsic contributions**

→ enhanced heat loss (phonons), reduced effective B coefficient

$$B_{eff} = N \cdot 2 \sum_{k_\perp} |\phi_{k_\perp}|^2 \Omega_{k_\perp}^3 (\pi e \hbar c^3)^{-1} n_{e,k_\perp} n_{h,k_\perp}$$

Contributions to LED Efficiency Dependence on Temperature

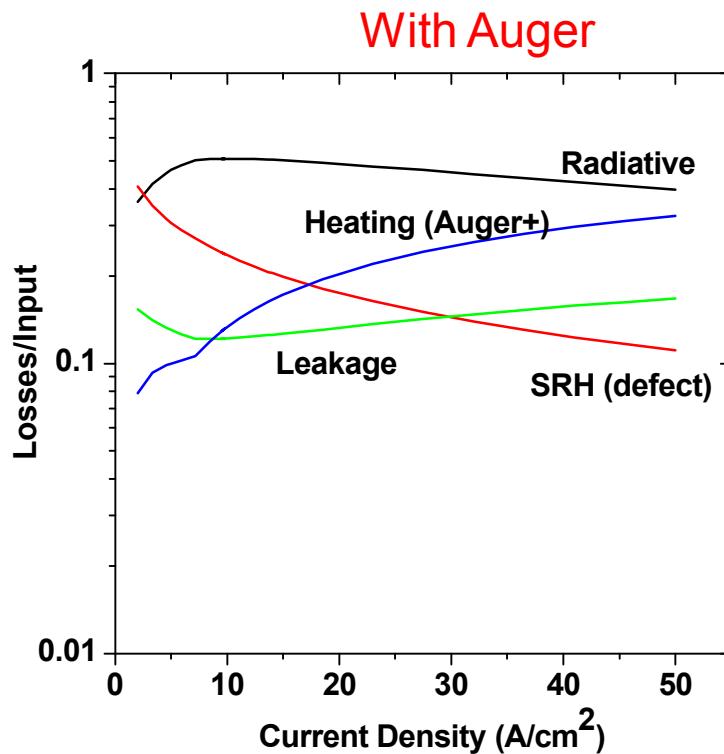
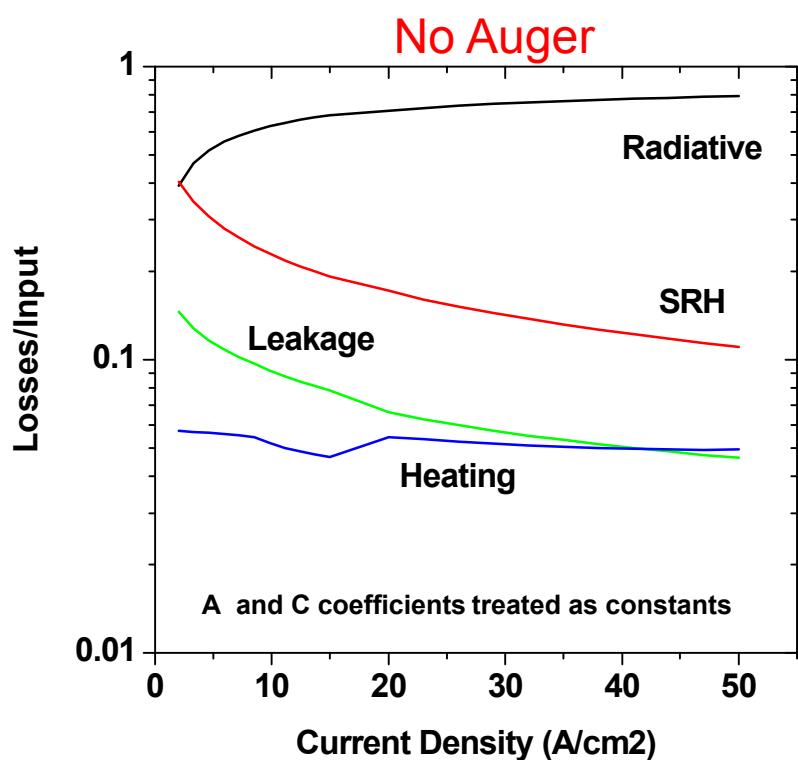
Assumptions: In $\text{In}_{0.1}\text{Ga}_{0.9}\text{N}$ QW LED (violet) $J = 100 \text{ A/cm}^2$ $T = 450\text{K}$



- Model quantifies **plasma heating** at high current densities (100 A/cm^2)
- Quantifies contributions to lower efficiency at elevated temperatures:
→ carrier leakage out of QWs, reduced B_{eff}

Interdependences of Loss Contributions

$\text{In}_{0.1}\text{Ga}_{0.9}\text{N QW}$



- For violet QWs, losses due to phonon emission (heating) is minimal up to 50 A/cm² in the absence of Auger recombination
- Auger-related heating drives enhanced carrier leakage

II. Potential Role of Defects in Efficiency Droop

LED rate-equation model

$$\frac{dN}{dt} = \frac{J}{ed} - AN - BN^2 - CN^3$$

Defects Spontaneous emission Auger?

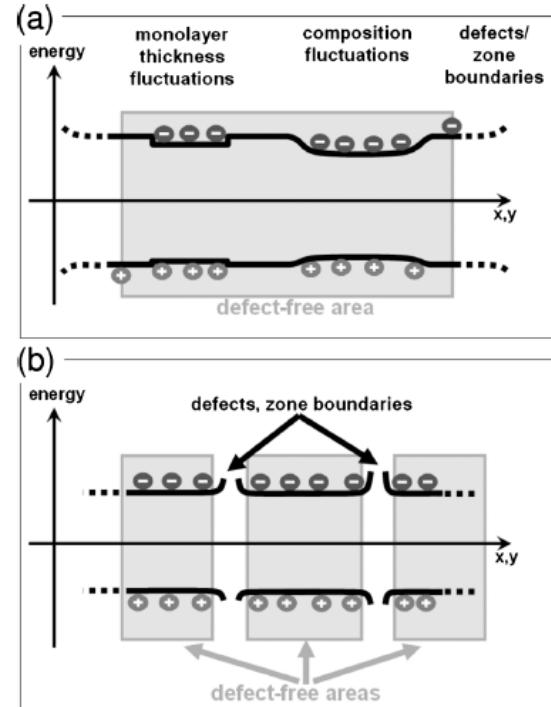
Internal quantum efficiency = $\frac{BN^2}{AN + BN^2 + CN^3}$

Questions:

- *Can defects contribute nonlinear terms in the absence of localization?*
- *What defect properties are required to impact efficiency in the droop regime?*

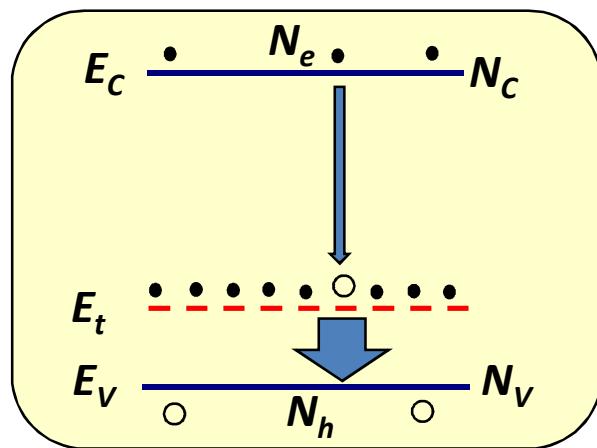
Density-Activated Defect Recombination

$$J_{\text{DADR}} = \begin{cases} 0, & \text{for } N < N_0 \\ \frac{en_w}{\tau_{\text{DADR}}} \frac{(N - N_0)^2}{2N_0}, & \text{for } N > N_0 \end{cases}$$



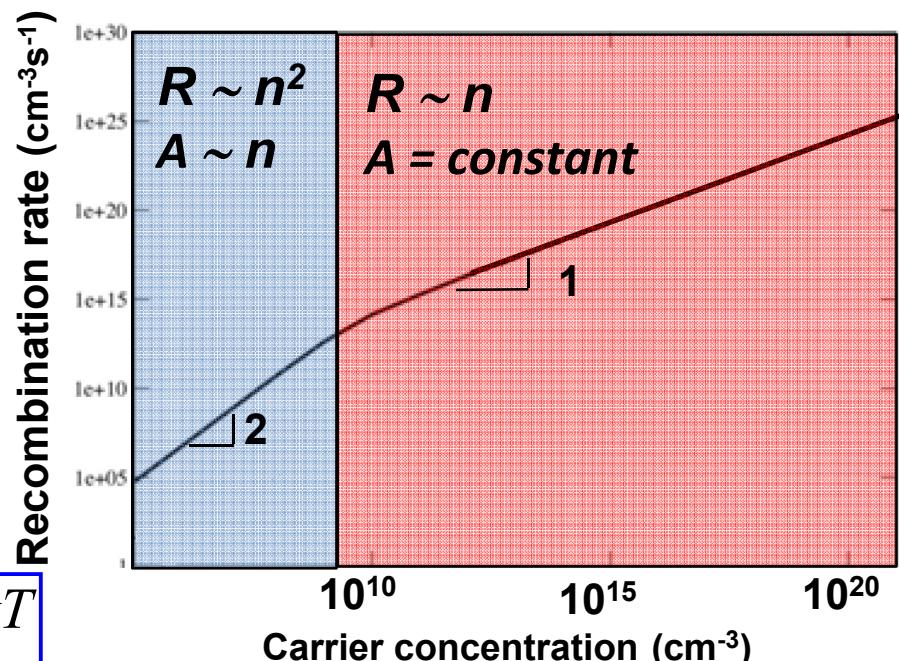
Hader et al., APL 2011

Basic SRH Theory Predicts A(n)



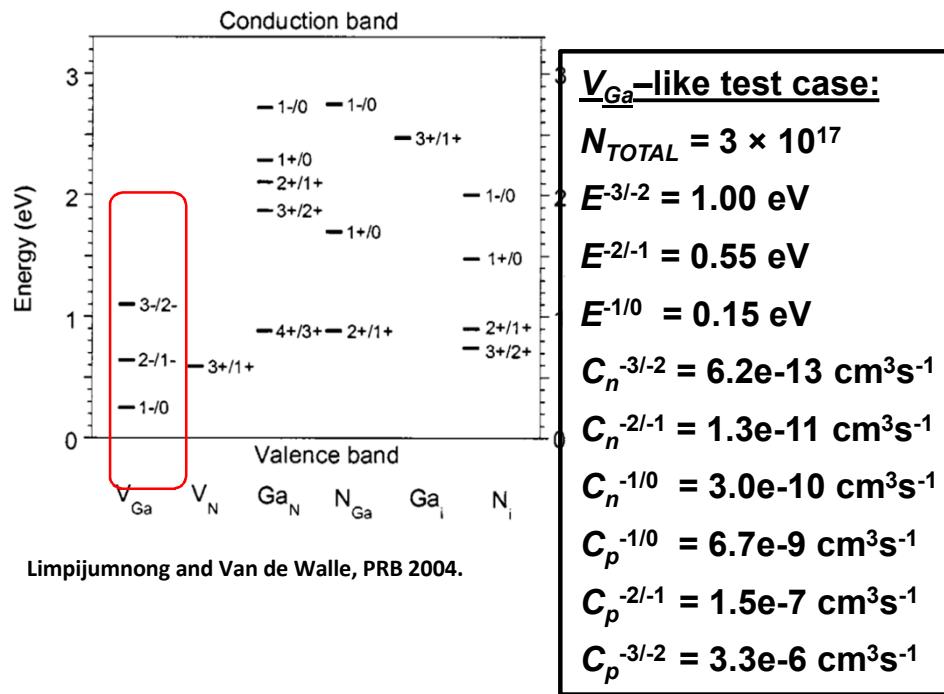
For $N_e = N_h = n \ll N_V \exp(E_v - E_t)/kT$

$$R_{SRH} \approx \frac{n^2}{\tau_{n0} N_V \exp(E_v - E_t)/kT}$$



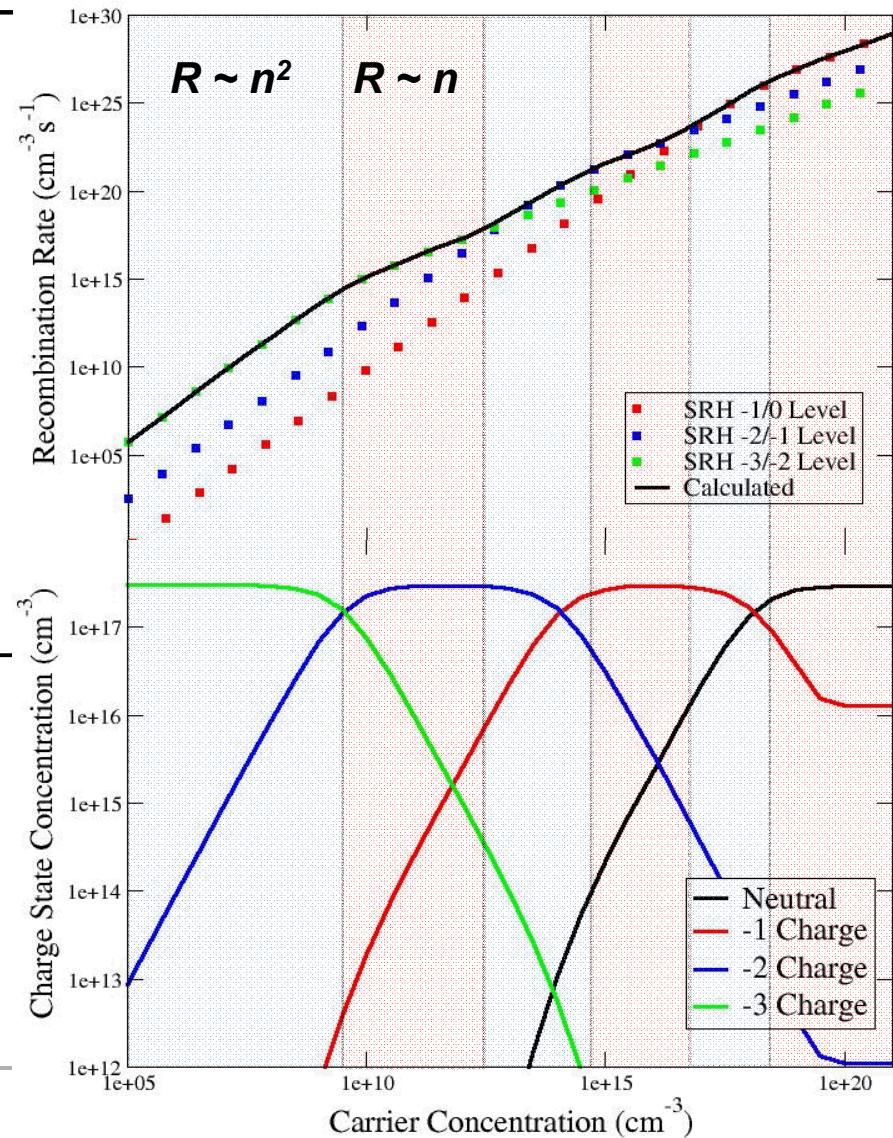
- $R \sim n^2$ when hole emission outpaces hole capture
- A is not constant even for simple defects
- BUT, simple defects cannot explain droop

What About Multilevel Defects?



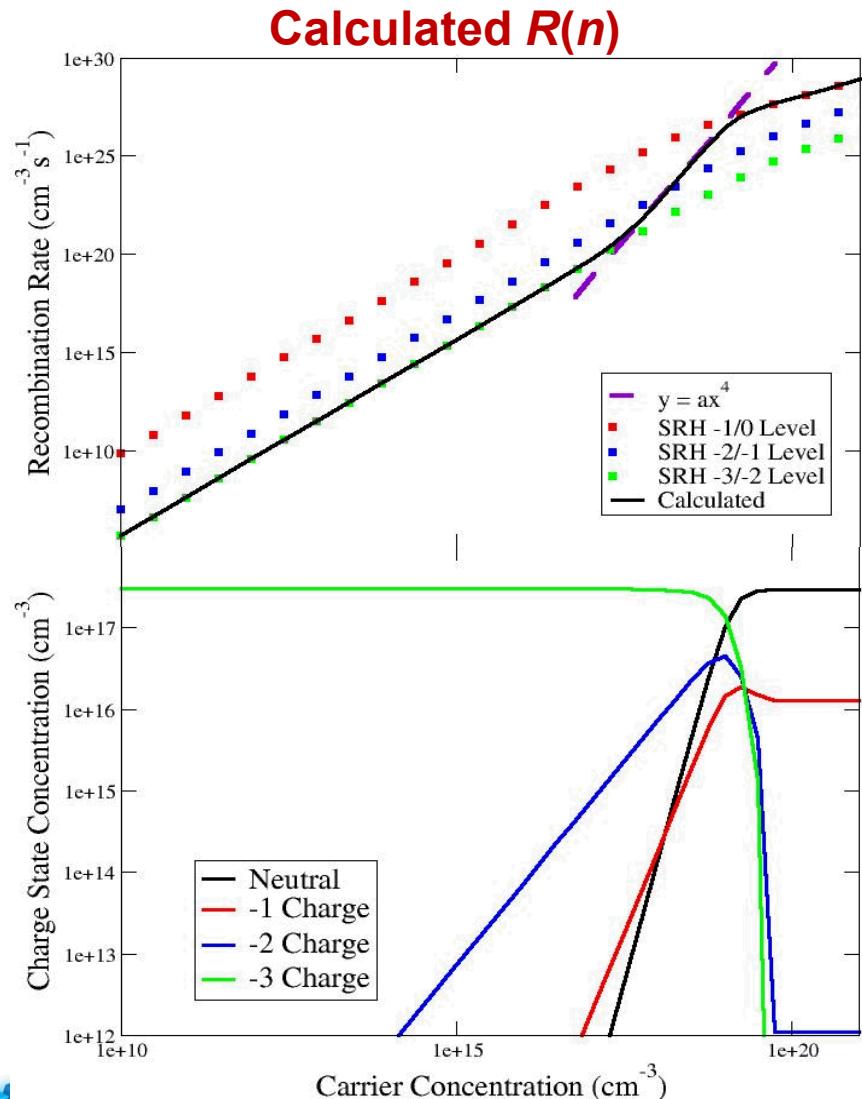
Limpijumnong and Van de Walle, PRB 2004.

Calculated $R(n)$

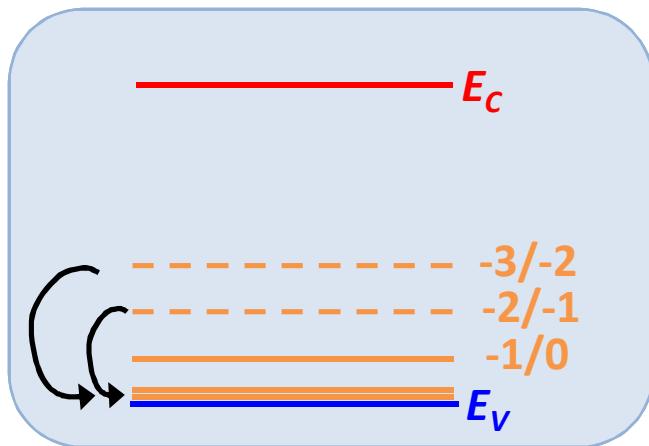


- Multiple $R \sim n^2$ regimes
- Summing SRH rates gives decent approximation
- Shallow levels have n^2 to n cross-over at larger n
- Still not $R \sim n^2$

What About Negative-U Defects?



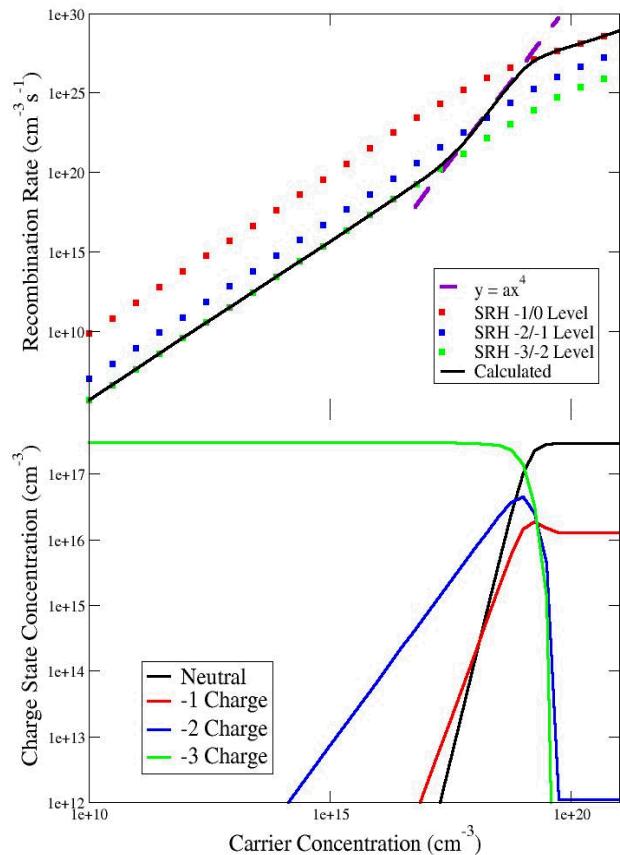
Defect Energy Levels



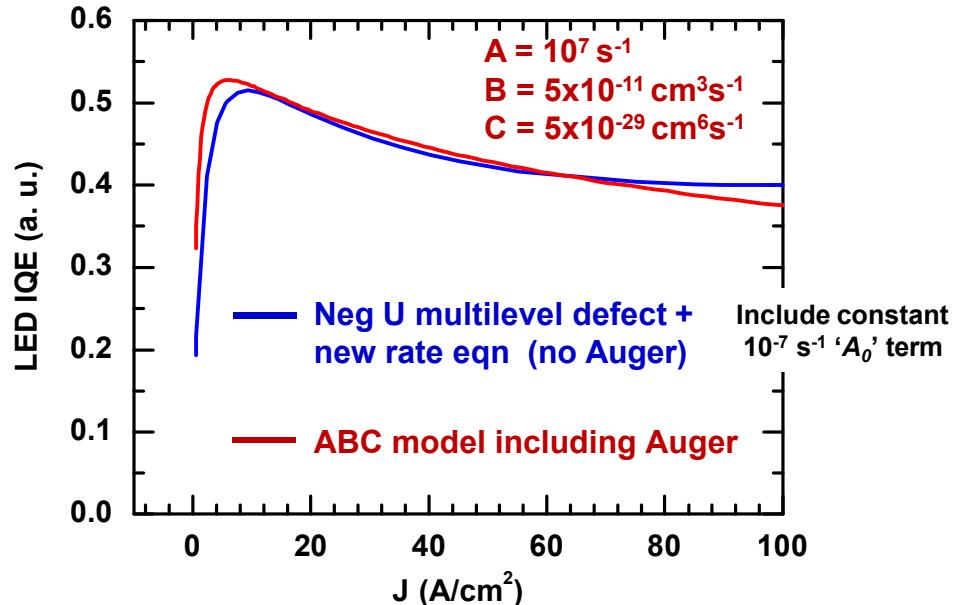
- -U behavior makes the -2 and -1 charge states unstable
- Shallow levels keep defect in -3 state until $10^{18} - 10^{19} \text{ cm}^{-3}$ carriers
- Defect recombination requires $3h^+ + e^-$ giving $R \sim n^4$
- Combined conditions sufficient to contribute in the droop regime

Influence of $A(n)$ on LED IQE

Calculated $R(n)$ --Negative U defect



Comparing two models for LED IQE

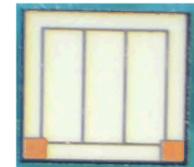


- Multilevel defect can contribute to droop, given:
 - **Negative-U defect**
 - **Sufficiently shallow defect level**
- **Auger or other n^2 mechanism still required** at highest currents to match experiments

Summary

- Modified rate equation model enables insights into contributions to reduced LED efficiency up to high carrier densities; impact of bandstructure and plasma heating on:
 - LED efficiency versus wavelength
 - LED efficiency at elevated temperatures
 - Impact of Auger on other loss terms , including radiative recombination and leakage
- Explored conditions for non-linear loss via recombination at defects without invoking carrier localization
 - multi-level defect with negative U behavior, V_{Ga} –like defect, $R \sim n^4$
 - Shallow defect to delay nonlinear contribution to high carrier densities ($1e18-1e19 \text{ cm}^{-3}$)
 - may contribute to higher order coefficients

LED Chip



Packaged LED



Luminaires



Figures from DOE EERE SSL MYPP March 2010

